

Search Notes

Application/Control No.

10/571,195

Examiner

Patricia Leith

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

1655

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCBACKFILE	11/20/2007	PL
Inventor name search PALM/EAST	11/20/2007	PL
STN: Indexed BIOSCIENCE cluster & Napralert database (approx. 68 databases)	11/20/2007	PL